## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10786609	NAKANO ET AL.	
Examiner	Art Unit	
Nguyen, Jennifer T	2629	

SEARCHED							
Class	Class Subclass		Examiner				
345	93-96,87,89-92,89,100,204,212,690-692,53,54,55,58	1/4/08	JN				

SEARCH NOTES					
Search Notes	Date	Examiner			
East search, PAJ,EPO, US-PAT, PG-PUB, DERWENT, inventor, claim interference	1/4/08	JN			

INTERFERENCE SEARCH						
Class		Subclass	Date	Examiner		
341	144		1/4/08	jn		